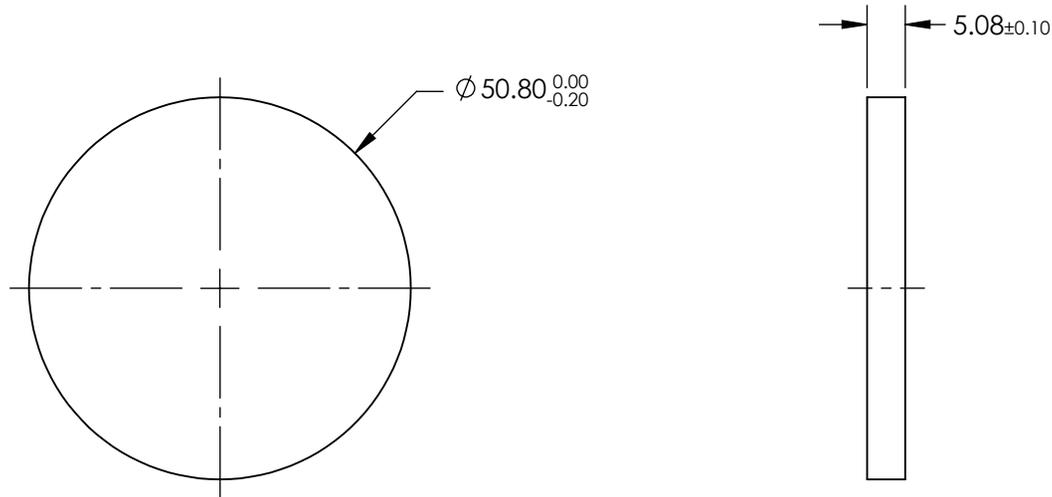


NOTES:

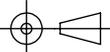
1. SUBSTRATE:  
Fused Silica
2. COATING (APPLY ACROSS CLEAR APERTURE)  
  
S1 & S2: Dielectric Multilayer AR
3. ROHS COMPLIANT



**FOR INFORMATION ONLY:  
DO NOT MANUFACTURE  
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE  
DIMENSIONS ARE FOR REFERENCE ONLY

**EO**® Edmund Optics®

	S1	S2	THIRD ANGLE PROJECTION 		TITLE	20-40nm, 50.8mm Dia, EUV/IR Dichroic Filter	
SHAPE	PLANO	PLANO	ALL DIMS IN	mm	DWG NO	18280	SHEET 1 OF 1
SURFACE QUALITY	20-10	20-10					
BEVEL	PROTECTED AS NEEDED	PROTECTED AS NEEDED					